

Press Release

San Jose, CA July 18, 2004

Photon Announces New 2-D and 3-D Visualization Added to NanoScan Beam Profiler



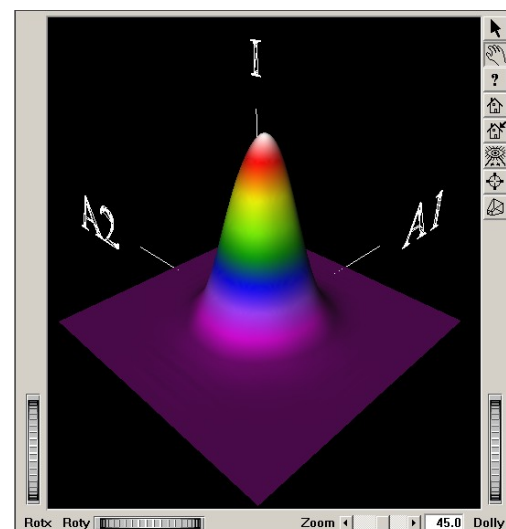
San Jose, CA - Photon, a leading manufacturer of beam profiling optical test equipment announces the addition of 2-Dimensional and 3-Dimensional beam profile visualization to its NanoScan Beam Profiler. The NanoScan employs the scanning slit beam profiling technique, which generates two orthogonal linear profiles. This data becomes more intuitive when 2-Dimensional and 3-Dimensional images are generated from these profiles. For active optical alignment, this qualitative information has been shown to be especially useful. For these reasons, the standard NanoScan software package now includes this important new visualization tool.

The Photon NanoScan is a sub-micron resolution profiler used to align optics and characterize lasers in a wide variety of applications. The NanoScan has three detector options: a silicon detector for operation at 350-1000 nm wavelengths, a germanium detector for 700-1800nm wavelengths, and a pyroelectric detector for 190nm – 20+ micron wavelengths. The NanoScan accurately measures continuous wave beams as small as 4 microns and as large as 20mm, and pulsed beams are also measured with the NanoScan. Powers as low as a few micro Watts, or as high as few kilowatts can be measured with appropriate NanoScan models.

Photon is located in San Jose, California in the United States and has supplied beam profiling instrumentation for over 20 years to the laser and photonics communities. Photon has earned several patents and new product awards for innovations over this period.

Contact: Mary Russell
Phone 418.226.1000, x120
Fax 408.226.1025
mrussell@photon-inc.com

**For Immediate Release
July 18, 2004**



3-D representation of a beam generated by the NanoScan.

◆◆◆